				NU
	Application	No.	Applicant(s)	
Notice of Allowability	10/075 140		CDEENE ET AL	
	10/075,142 Examiner		GREENE ET AL.  Art Unit	1
	Jennifer Do	an	2874	L
The MAILING DATE of this communication at All claims being allowable, PROSECUTION ON THE MERITS herewith (or previously mailed), a Notice of Allowance (PTOLNOTICE OF ALLOWABILITY IS NOT A GRANT OF PATEN of the Office or upon petition by the applicant. See 37 CFR 1	S IS (OR REMAINS -85) or other appro <b>T RIGHTS</b> . This a	S) CLOSED in this a opriate communication of the second o	application. If not includ on will be mailed in due	ed course. <b>THIS</b>
1. This communication is responsive to <u>amendment filed</u>	on 08/18/03.			
2. The allowed claim(s) is/are 1-20 and 22-32.				
3. The drawings filed on <u>02/14/2002</u> are accepted by the Examiner.				
<ul> <li>4. ☐ Acknowledgment is made of a claim for foreign priority</li> <li>a) ☐ All b) ☐ Some* c) ☐ None of the:</li> </ul>	under 35 U.S.C. {	§ 119(a)-(d) or (f).		
<ol> <li>Certified copies of the priority documents in</li> </ol>	have been receive	d.		
2.  Certified copies of the priority documents have been received in Application No				
<ol><li>Copies of the certified copies of the priority</li></ol>	y documents have	been received in thi	is national stage applica	ation from the
International Bureau (PCT Rule 17.2(a)	)).			
* Certified copies not received:				
5. Acknowledgment is made of a claim for domestic priori	ity under 35 U.S.C	. § 119(e) (to a prov	risional application).	
(a) The translation of the foreign language provision				
6. Acknowledgment is made of a claim for domestic priori	ity under 35 U.S.C	. §§ 120 and/or 121	•	
Applicant has THREE MONTHS FROM THE "MAILING DATE below. Failure to timely comply will result in ABANDONMEN"				
7. A SUBSTITUTE OATH OR DECLARATION must be s INFORMAL PATENT APPLICATION (PTO-152) which gives				NOTICE OF
8. CORRECTED DRAWINGS must be submitted.				
(a) including changes required by the Notice of Drafts	sperson's Patent D	Drawing Review ( P1	O-948) attached	
1)  hereto or 2)  to Paper No	•	,		
(b) including changes required by the proposed draw	ing correction filed	d, which has	been approved by the	Examiner.
(c) 🔲 including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No				
Identifying indicia such as the application number (see 37 C	FR 1.84(c)) should	be written on the dra	wings in the front (not th	e back) of
3331 511331.				
9. DEPOSIT OF and/or INFORMATION about the d attached Examiner's comment regarding REQUIREMENT FO				Note the
Attachment(s)				
1⊠ Notice of References Cited (PTO-892)		2☐ Notice of Infor	mal Patent Application	(PTO-152)
3☐ Notice of Draftperson's Patent Drawing Review (PTO-94		4 Interview Sum	nmary (PTO-413), Pape	
5 Information Disclosure Statements (PTO-1449), Paper N			mendment/Comment	. A.H
7 Examiner's Comment Regarding Requirement for Depos of Biological Material	sit	8⊠ Examiner's St 9∏ Other .	atement of Reasons for	Allowance

B 10/08/03 JD

Page 2

Application/Control Number: 10/075,142

Art Unit: 2874

## **EXAMINER'S AMENDMENT AND STATEMENT OF REASONS FOR ALLOWANCE**

## Examiner's amendment

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Jon P. Christensen on October 7, 2003.

The application has been amended as follows:

Cancel claim 21.

In claim 20, line 11, after "...the alignment fixture", please delete ".", and insert — wherein the step of aligning the substrate to the fixture further comprises providing a plurality of passive alignment guide pins in the alignment fixture and inserting the plurality of passive alignment guide pins through a respective plurality alignment apertures in the substrate. --

In claim 22, line 1, please delete "21" and insert – 20 --.

In claim 26, line 3, please delete "means" and insert -- a first optical recognition module --.

In claim 26, line 4, please delete "means" and insert -- a second optical recognition module --.

Art Unit: 2874

·

## Reasons for allowance

2. The following is an examiner's statement of reasons for allowance:

The prior art of record fails to disclose or reasonably suggest an apparatus and a method of aligning an optical array with a substrate comprising aligning the substrate with a set of alignment structures on an alignment fixture; transmitting a plurality of optical signals from the fixture through the aligned substrate; determining a location of the transmitted optical signals and the optical array; aligning the optical array to the substrate based upon the determined locations of the transmitted plurality of optical signals and optical array using a pick and place machine; further identifying a first plurality of registration marks in the alignment fixture with a first optical recognition module and identifying a second plurality of registration marks on the optical array with a second optical recognition module as recited in claims 1, 11, 20 and 26.

The examiner agrees with applicants' arguments on pages 2 and 3 in the remarks accompanying the amendment of August 18, 2003, and fully concurs that the Wickman et al. reference does not disclose or suggest the highlighted limitations above.

The newly cited references, Moisel (U.S. Patent 6,236,788) discloses an arrangement, which permits a simple and precise alignment of optical components to each other; however, Moisel does not disclose or suggest the highlighted limitations above.

Application/Control Number: 10/075,142

Art Unit: 2874

Ukechi et al. (U.S. Patent 6,324,314) disclose an optical hybrid integrated device having a first substrate with a semiconductor optical element and alignment marks and a second substrate with an optical waveguide and alignment marks formed on the second substrate (as shown in Fig. 3); nevertheless, Ukechi et al. do not explicitly teach an optical module used to identify the alignment marks on the first and second substrates for aligning and attaching the first and second substrates. Thus, the Ukechi reference also fails to disclose or suggest the highlighted limitations above.

Claims 1-20 and 22-32 are therefore allowed.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## Conclusion

3. Any inquiry concerning the merits of this communication should be directed to Examiner Jennifer Doan whose telephone number is (703) 308-6179. The examiner can normally be reached on Monday to Friday from 6:00am to 3:30pm, second Friday off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Rodney Bovernick, can be reached on (703) 308-4819. The fax phone number for the organization where this application or proceeding is assigned is (703) 308-7724.

Art Unit: 2874

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

JD

October 8, 2003

Jennifer Doan